

<b>Notice of References Cited</b>	Application/Control No. 10/699,813	Applicant(s)/Patent Under Reexamination JEON ET AL.	
	Examiner Prabodh M. Dharia	Art Unit 2629	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,300,928	10-2001	Kim, Young Dae	345/92
*	B	US-6,741,229	05-2004	Yanagi et al.	345/98
*	C	US-5,736,972	04-1998	Kitagishi et al.	345/99
*	D	US-5,912,651	06-1999	Bitzakidis et al.	345/58
*	E	US-6,014,126	01-2000	Nishihara, Yasutomo	345/698
*	F	US-6,078,304	06-2000	Miyazawa, Kuniaki	345/88
*	G	US-4,924,214	05-1990	Hill, Lennard C.	340/666
*	H	US-5,648,794	07-1997	Jelsma et al.	345/98
*	I	US-5,963,184	10-1999	Tokunaga et al.	345/60
*	J	US-6,295,042	09-2001	Aoki, Tadashi	345/60
*	K	US-6,339,631	01-2002	Yeo et al.	377/64
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.